







CSD88539ND SLPS456A - FEBRUARY 2014 - REVISED DECEMBER 2023

CSD88539ND Dual 60 V N-Channel NexFET™ Power MOSFETs

1 Features

- Ultra-Low Q_g and Q_{gd}
- Avalanche Rated
- Pb Free
- **RoHS Compliant**
- Halogen Free

2 Applications

- Half Bridge for Motor Control
- Synchronous Buck Converter

3 Description

This dual SO-8, 60 V, 23 mΩ NexFET™ power MOSFET is designed to serve as a half bridge in lowcurrent motor control applications.

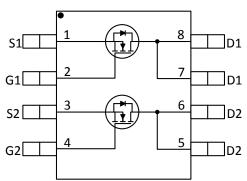
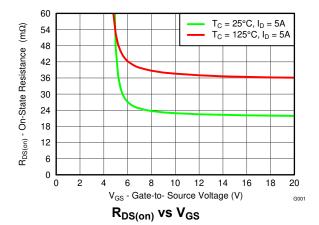


Figure 3-1. Top View



Product Summary

T _A = 25°	С	TYPICAL VA	UNIT	
V _{DS}	Drain-to-Source Voltage 60			V
Qg	Gate Charge Total (10 V)	7.2		nC
Q _{gd}	Gate Charge Gate to Drain	1.1	nC	
Б	Drain-to-Source On Resistance	V _{GS} = 6 V 27		mΩ
R _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V	23	mΩ
V _{GS(th)}	Threshold Voltage	3.0	V	

Ordering Information⁽¹⁾

Device	Qty	Media	Package	Ship	
CSD88539ND	2500	13-Inch Reel	SO-8 Plastic	Tape and	
CSD88539NDT	250	7-Inch Reel	Package	Reel	

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Absolute Maximum Ratings

7 toodiato maximam ratingo								
T _A = 2	5°C	VALUE	UNIT					
V_{DS}	Drain-to-Source Voltage	60	V					
V _{GS}	Gate-to-Source Voltage	±20	V					
	Continuous Drain Current (Package limited)	15						
I _D	Continuous Drain Current (Silicon limited), T _C = 25°C	11.7	Α					
	Continuous Drain Current ⁽¹⁾	6.3						
I _{DM}	Pulsed Drain Current (2)	46	Α					
P _D	Power Dissipation ⁽¹⁾	2.1	W					
T _J , T _{STG}	Operating Junction and Storage Temperature Range	-55 to 150	°C					
E _{AS}	Avalanche Energy, single pulse $I_D = 22$ A, L = 0.1 mH, $R_G = 25$ Ω	24	mJ					

- Typical $R_{\theta JA} = 60^{\circ}$ C/W on a 1-inch², 2-oz. Cu pad on a 0.06inch thick FR4 PCB
- Pulse duration ≤300 µs, duty cycle ≤2%

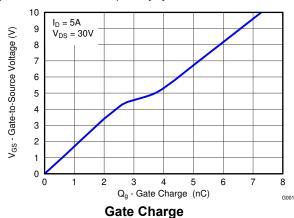




Table of Contents

1 Features1	4.3 Typical MOSFET Characteristics4
2 Applications 1	5 Device and Documentation Support
3 Description1	
4 Specifications3	5.2 Electrostatic Discharge Caution
4.1 Electrical Characteristics3	6 Revision History7
4.2 Thermal Information3	

4 Specifications

4.1 Electrical Characteristics

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	CHARACTERISTICS					
BV _{DSS}	Drain-to-Source Voltage	V _{GS} = 0 V, I _D = 250 μA	60			V
I _{DSS}	Drain-to-Source Leakage Current	V _{GS} = 0 V, V _{DS} = 48 V			1	μA
I _{GSS}	Gate-to-Source Leakage Current	V _{DS} = 0 V, V _{GS} = 20 V			100	nA
V _{GS(th)}	Gate-to-Source Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.6	3.0	3.6	V
n	Drain-to-Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 5 \text{ A}$		27	34	mΩ
R _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 5 A		23	28	mΩ
9 _{fs}	Transconductance	V _{DS} = 30 V, I _D = 5 A		19		S
DYNAM	C CHARACTERISTICS	'				
C _{iss}	Input Capacitance			570	741	pF
C _{oss}	Output Capacitance	$V_{GS} = 0 \text{ V, } V_{DS} = 30 \text{ V, } f = 1 \text{ MHz}$		70	91	pF
C _{rss}	Reverse Transfer Capacitance			2.0	2.6	pF
R_G	Series Gate Resistance			6.6	13.2	Ω
Q_g	Gate Charge Total (10 V)			7.2	9.4	nC
Q _{gd}	Gate Charge Gate to Drain	V 20 V I 5 A		1.1		nC
Q _{gs}	Gate Charge Gate to Source	V _{DS} = 30 V, I _D = 5 A		2.7		nC
Q _{g(th)}	Gate Charge at V _{th}			1.8		nC
Q _{oss}	Output Charge	V _{DS} = 30 V, V _{GS} = 0 V		9.6		nC
t _{d(on)}	Turn On Delay Time			5		ns
t _r	Rise Time	V - 20 V V - 40 V L - 5 A B - 0.0		9		ns
t _{d(off)}	Turn Off Delay Time	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_{DS} = 5 \text{ A}, R_G = 0 \Omega$		14		ns
t _f	Fall Time			4		ns
DIODE (CHARACTERISTICS	<u> </u>	<u> </u>			
V _{SD}	Diode Forward Voltage	I _{SD} = 5 A, V _{GS} = 0 V		0.8	1	V
Q _{rr}	Reverse Recovery Charge	V = 20 V I = 54 di/dt = 2004/va		37		nC
t _{rr}	Reverse Recovery Time			21		ns

4.2 Thermal Information

(T_A = 25°C unless otherwise stated)

	THERMAL METRIC	MIN	TYP	MAX	UNIT
$R_{\theta JL}$	Junction-to-Lead Thermal Resistance ⁽¹⁾			20	°C/W
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance ⁽¹⁾ (2)			75	C/VV

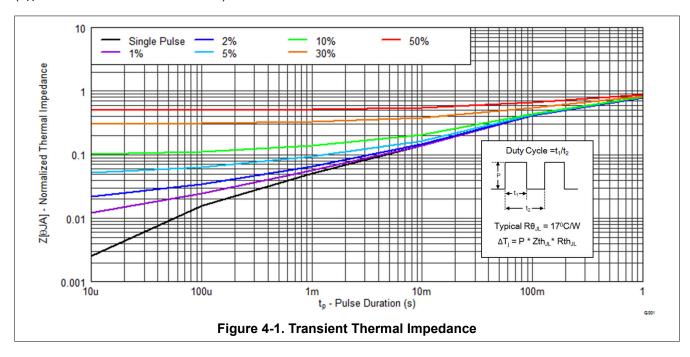
R_{0JC} is determined with the device mounted on a 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 1.5-inch × 1.5-inch (3.81-cm × 3.81-cm), 0.06-inch (1.52-mm) thick FR4 PCB. R_{θJC} is specified by design, whereas R_{θJA} is determined by the user's board design.

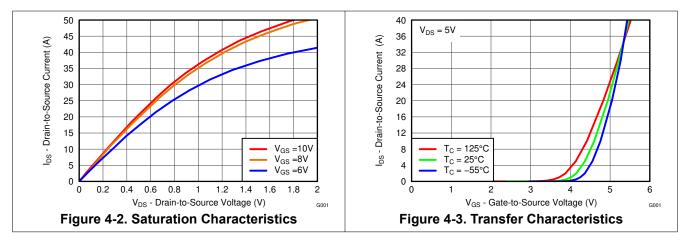
(2) Device mounted on FR4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu.

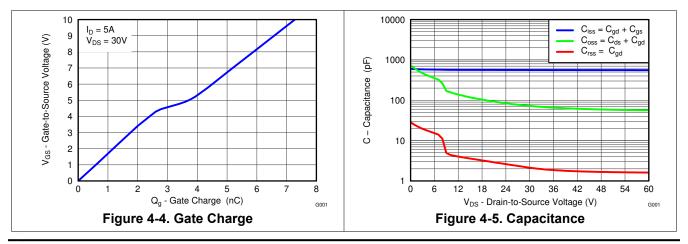


4.3 Typical MOSFET Characteristics

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$









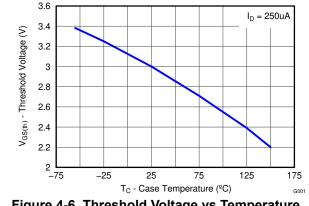


Figure 4-6. Threshold Voltage vs Temperature

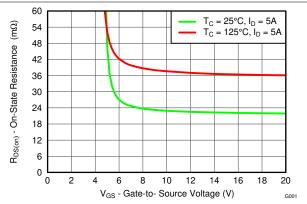


Figure 4-7. On-State Resistance vs Gate-to-Source Voltage

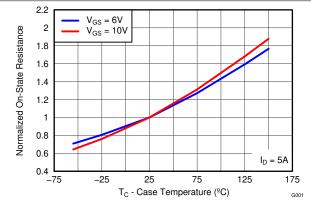


Figure 4-8. Normalized On-State Resistance vs **Temperature**

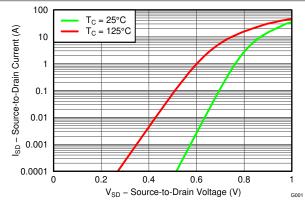


Figure 4-9. Typical Diode Forward Voltage

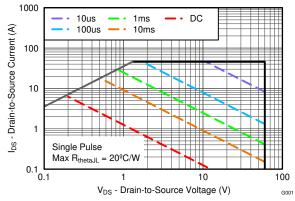


Figure 4-10. Maximum Safe Operating Area

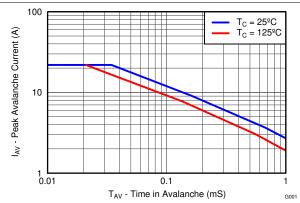
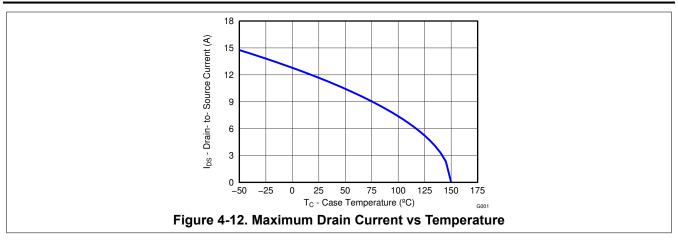


Figure 4-11. Single Pulse Unclamped Inductive **Switching**







5 Device and Documentation Support

5.1 Trademarks

NexFET[™] is a trademark of Texas Instruments. All trademarks are the property of their respective owners.

5.2 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

6 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (February 2014) to Revision A (December 2023)

Page

7 Mechanical Data

www.ti.com 9-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
CSD88539ND	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 150	88539N
CSD88539ND.B	Active	Production	SOIC (D) 8	2500 LARGE T&R	-	Call TI	Call TI	-55 to 150	
CSD88539NDG4	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 150	88539N
CSD88539NDG4.B	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 150	88539N
CSD88539NDT	Active	Production	SOIC (D) 8	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 150	88539N
CSD88539NDT.B	Active	Production	SOIC (D) 8	250 SMALL T&R	-	Call TI	Call TI	-55 to 150	

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

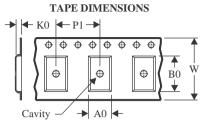
www.ti.com 9-Nov-2025

PACKAGE MATERIALS INFORMATION

www.ti.com 7-Dec-2023

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

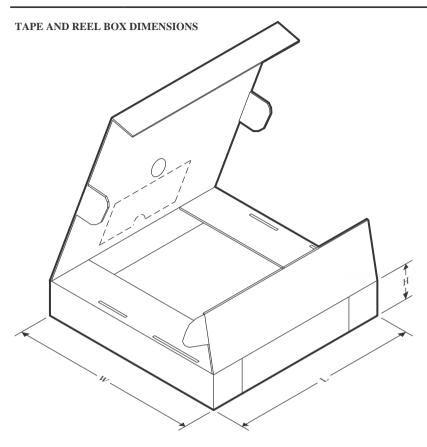


*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CSD88539NDT	SOIC	D	8	250	178.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 7-Dec-2023



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CSD88539NDT	SOIC	D	8	250	180.0	180.0	79.0	



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale, TI's General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2025, Texas Instruments Incorporated

Last updated 10/2025